

A revolution for chemical analysis

Geneva, Thursday November 14th, 2019 the Laboratoire de Technologie Avancée (LTA) launched its High-Performance Chemical Analysis and Imaging Platform, which has capabilities unique in Switzerland.

The two latest technologies a PHI nanoTOF II TOF-SIMS mass spectrometer with parallel MS/MS imaging and a PHI VersaProbe III scanning XPS microprobe astonished around 70 participants at the Ecole de physique. Half of them comes from industry and the other half from University/Institutes. LTA's platform combines expertise in the field of molecular identification and surface chemistry. Both academic and industrial laboratories will be able to take advantage of what this equipment has to offer, and the scientific know-how of this platform, to meet their technological challenges in a wide range of fields of activity.

The attendees were greeted and guided through the whole day by Prof. Dr. Christoph Renner, Professor at the University of Geneva, Department of Quantum Matter Physics. There were interesting discussions and a valuable exchange. The LTA introduced its two scientists, Dr. Siobhan McKeown Walker senior scientist for the XPS and Dr. Andras Kiss senior scientist for the TOF-SIMS. Their talks showed the first results achieved with the platform. Although both devices have only been installed for a month, the results have been very impressive.



A special guest was Dr. Scott R. Bryan, President of Physical Electronics USA. Physical Electronics USA is a subsidiary of ULVAC-PHI, the supplier of both instruments. Over the past 30 years Scott has published 50 peer reviewed papers and made numerous presentations at both national and international conferences. His talk: Advances in XPS and TOF-SIMS for Surface Chemical Analysis delighted the audience. The last session on the agenda was the highlight of the day. The TOF-SIMS were accessed via remote control in the laboratory. Scott and Andras showed different live measurements. The speed and their know how impressed everyone. Finally, there was a lab tour to see the hardware of the XPS and TOF-SIMS and the beautiful facilities of the LTA's surface science lab.

A special thanks goes to Dr. Jeremie Teyssier, scientific liaison officer at the LTA.

Physical Electronics GmbH wishes all those responsible at the LTA, every success with their platform. We are all sure, that we will hear a lot more about this wonderful platform and its users in the future. In 2020 already a NanoX-Perience TOF-SIMS and XPS seminar is planned, come and discover the potential of this new platform. Information on this will be announced soon.

